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Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	533MHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	672-LBGA
Supplier Device Package	672-LBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8349vvajfb

- Double data rate, DDR1/DDR2 SDRAM memory controller
 - Programmable timing supporting DDR1 and DDR2 SDRAM
 - 32- or 64-bit data interface, up to 400 MHz data rate
 - Up to four physical banks (chip selects), each bank up to 1 Gbyte independently addressable
 - DRAM chip configurations from 64 Mbits to 1 Gbit with $\times 8/\times 16$ data ports
 - Full error checking and correction (ECC) support
 - Support for up to 16 simultaneous open pages (up to 32 pages for DDR2)
 - Contiguous or discontiguous memory mapping
 - Read-modify-write support
 - Sleep-mode support for SDRAM self refresh
 - Auto refresh
 - On-the-fly power management using CKE
 - Registered DIMM support
 - 2.5-V SSTL2 compatible I/O for DDR1, 1.8-V SSTL2 compatible I/O for DDR2
- Dual three-speed (10/100/1000) Ethernet controllers (TSECs)
 - Dual controllers designed to comply with IEEE 802.3™, 802.3u™, 802.3x™, 802.3z™, 802.3ac™ standards
 - Ethernet physical interfaces:
 - 1000 Mbps IEEE Std. 802.3 GMII/RGMII, IEEE Std. 802.3z TBI/RTBI, full-duplex
 - 10/100 Mbps IEEE Std. 802.3 MII full- and half-duplex
 - Buffer descriptors are backward-compatible with MPC8260 and MPC860T 10/100 programming models
 - 9.6-Kbyte jumbo frame support
 - RMON statistics support
 - Internal 2-Kbyte transmit and 2-Kbyte receive FIFOs per TSEC module
 - MII management interface for control and status
 - Programmable CRC generation and checking
- Dual PCI interfaces
 - Designed to comply with *PCI Specification Revision 2.3*
 - Data bus width options:
 - Dual 32-bit data PCI interfaces operating at up to 66 MHz
 - Single 64-bit data PCI interface operating at up to 66 MHz
 - PCI 3.3-V compatible
 - PCI host bridge capabilities on both interfaces
 - PCI agent mode on PCI1 interface
 - PCI-to-memory and memory-to-PCI streaming
 - Memory prefetching of PCI read accesses and support for delayed read transactions
 - Posting of processor-to-PCI and PCI-to-memory writes

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings¹

Parameter		Symbol	Max Value	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 1.32 (1.36 max for 667-MHz core frequency)	V	—
PLL supply voltage		AV_{DD}	–0.3 to 1.32 (1.36 max for 667-MHz core frequency)	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	–0.3 to 2.75 –0.3 to 1.98	V	—
Three-speed Ethernet I/O, MII management voltage		LV_{DD}	–0.3 to 3.63	V	—
PCI, local bus, DUART, system control and power management, I ² C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	—
Input voltage	DDR DRAM signals	MV_{IN}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	DDR DRAM reference	MV_{REF}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	–0.3 to ($LV_{DD} + 0.3$)	V	4, 5
	Local bus, DUART, CLKIN, system control and power management, I ² C, and JTAG signals	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	3, 5
	PCI	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	6
Storage temperature range		T_{STG}	–55 to 150	°C	—

Notes:

- ¹ Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- ² **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ³ **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁴ **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁵ (M,L,O) V_{IN} and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
- ⁶ OV_{IN} on the PCI interface can overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in Figure 3.

- ² Typical power is based on a voltage of $V_{DD} = 1.2$ V, a junction temperature of $T_J = 105^\circ\text{C}$, and a Dhrystone benchmark application.
- ³ Thermal solutions may need to design to a value higher than typical power based on the end application, T_A target, and I/O power.
- ⁴ Maximum power is based on a voltage of $V_{DD} = 1.2$ V, worst case process, a junction temperature of $T_J = 105^\circ\text{C}$, and an artificial smoke test.
- ⁵ Typical power is based on a voltage of $V_{DD} = 1.3$ V, a junction temperature of $T_J = 105^\circ\text{C}$, and a Dhrystone benchmark application.
- ⁶ Maximum power is based on a voltage of $V_{DD} = 1.3$ V, worst case process, a junction temperature of $T_J = 105^\circ\text{C}$, and an artificial smoke test.

Table 5 shows the estimated typical I/O power dissipation for MPC8349EA.

Table 5. MPC8349EA Typical I/O Power Dissipation

Interface	Parameter	GV_{DD} (1.8 V)	GV_{DD} (2.5 V)	OV_{DD} (3.3 V)	LV_{DD} (3.3 V)	LV_{DD} (2.5 V)	Unit	Comments
DDR I/O 65% utilization 2.5 V $R_s = 20\ \Omega$ $R_t = 50\ \Omega$ 2 pair of clocks	200 MHz, 32 bits	0.31	0.42	—	—	—	W	—
	200 MHz, 64 bits	0.42	0.55	—	—	—	W	—
	266 MHz, 32 bits	0.35	0.5	—	—	—	W	—
	266 MHz, 64 bits	0.47	0.66	—	—	—	W	—
	300 MHz, 32 bits	0.37	0.54	—	—	—	W	—
	300 MHz, 64 bits	0.50	0.7	—	—	—	W	—
	333 MHz, 32 bits	0.39	0.58	—	—	—	W	—
	333 MHz, 64 bits	0.53	0.76	—	—	—	W	—
	400 MHz, 32 bits	0.44	—	—	—	—	—	—
	400 MHz, 64 bits	0.59	—	—	—	—	—	—
PCI I/O load = 30 pF	33 MHz, 64 bits	—	—	0.08	—	—	W	—
	66 MHz, 64 bits	—	—	0.14	—	—	W	—
	33 MHz, 32 bits	—	—	0.04	—	—	W	Multiply by 2 if using 2 ports.
	66 MHz, 32 bits	—	—	0.07	—	—	W	
Local bus I/O load = 25 pF	133 MHz, 32 bits	—	—	0.27	—	—	W	—
	83 MHz, 32 bits	—	—	0.17	—	—	W	—
	66 MHz, 32 bits	—	—	0.14	—	—	W	—
	50 MHz, 32 bits	—	—	0.11	—	—	W	—
TSEC I/O load = 25 pF	MII	—	—	—	0.01	—	W	Multiply by number of interfaces used.
	GMII or TBI	—	—	—	0.06	—	W	
	RGMII or RTBI	—	—	—	—	0.04	W	
USB	12 MHz	—	—	0.01	—	—	W	Multiply by 2 if using 2 ports.
	480 MHz	—	—	0.2	—	—	W	
Other I/O	—	—	—	0.01	—	—	W	—

Table 9. RESET Pins DC Electrical Characteristics¹ (continued)

Parameter	Symbol	Condition	Min	Max	Unit
Output low voltage	V _{OL}	I _{OL} = 3.2 mA	—	0.4	V

Notes:

1. This table applies for pins $\overline{\text{PORESET}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$, and $\overline{\text{QUIESCE}}$.
2. $\overline{\text{HRESET}}$ and $\overline{\text{SRESET}}$ are open drain pins, thus V_{OH} is not relevant for those pins.

5.2 RESET AC Electrical Characteristics

Table 10 provides the reset initialization AC timing specifications of the MPC8349EA.

Table 10. RESET Initialization Timing Specifications

Parameter	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$ or $\overline{\text{SRESET}}$ (input) to activate reset flow	32	—	t _{PCI_SYNC_IN}	1
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to CLKIN when the MPC8349EA is in PCI host mode	32	—	t _{CLKIN}	2
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to PCI_SYNC_IN when the MPC8349EA is in PCI agent mode	32	—	t _{PCI_SYNC_IN}	1
$\overline{\text{HRESET}}$ / $\overline{\text{SRESET}}$ assertion (output)	512	—	t _{PCI_SYNC_IN}	1
$\overline{\text{HRESET}}$ negation to $\overline{\text{SRESET}}$ negation (output)	16	—	t _{PCI_SYNC_IN}	1
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of $\overline{\text{PORESET}}$ when the MPC8349EA is in PCI host mode	4	—	t _{CLKIN}	2
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of $\overline{\text{PORESET}}$ when the MPC8349EA is in PCI agent mode	4	—	t _{PCI_SYNC_IN}	1
Input hold time for POR configuration signals with respect to negation of $\overline{\text{HRESET}}$	0	—	ns	—
Time for the MPC8349EA to turn off POR configuration signals with respect to the assertion of $\overline{\text{HRESET}}$	—	4	ns	3
Time for the MPC8349EA to turn on POR configuration signals with respect to the negation of $\overline{\text{HRESET}}$	1	—	t _{PCI_SYNC_IN}	1, 3

Notes:

1. t_{PCI_SYNC_IN} is the clock period of the input clock applied to PCI_SYNC_IN. In PCI host mode, the primary clock is applied to the CLKIN input, and PCI_SYNC_IN period depends on the value of CFG_CLKIN_DIV. See the *MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual*.
2. t_{CLKIN} is the clock period of the input clock applied to CLKIN. It is valid only in PCI host mode. See the *MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual*.
3. POR configuration signals consist of CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV.

Table 11 lists the PLL and DLL lock times.

Table 11. PLL and DLL Lock Times

Parameter/Condition	Min	Max	Unit	Notes
PLL lock times	—	100	μ s	—
DLL lock times	7680	122,880	csb_clk cycles	1, 2

Notes:

1. DLL lock times are a function of the ratio between the output clock and the coherency system bus clock (csb_clk). A 2:1 ratio results in the minimum and an 8:1 ratio results in the maximum.
2. The csb_clk is determined by the CLKIN and system PLL ratio. See [Section 19, “Clocking.”](#)

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface of the MPC8349EA. Note that DDR SDRAM is $GV_{DD}(\text{typ}) = 2.5 \text{ V}$ and DDR2 SDRAM is $GV_{DD}(\text{typ}) = 1.8 \text{ V}$. The AC electrical specifications are the same for DDR and DDR2 SDRAM.

NOTE

The information in this document is accurate for revision 3.0 silicon and later. For information on revision 1.1 silicon and earlier versions see the *MPC8349E PowerQUICC II Pro Integrated Host Processor Hardware Specifications*. See [Section 22.1, “Part Numbers Fully Addressed by This Document,”](#) for silicon revision level determination.

6.1 DDR and DDR2 SDRAM DC Electrical Characteristics

Table 12 provides the recommended operating conditions for the DDR2 SDRAM component(s) of the MPC8349EA when $GV_{DD}(\text{typ}) = 1.8 \text{ V}$.

Table 12. DDR2 SDRAM DC Electrical Characteristics for $GV_{DD}(\text{typ}) = 1.8 \text{ V}$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	1.71	1.89	V	1
I/O reference voltage	MV_{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF} + 0.125$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	−0.3	$MV_{REF} - 0.125$	V	—
Output leakage current	I_{OZ}	−9.9	9.9	μ A	4
Output high current ($V_{OUT} = 1.420 \text{ V}$)	I_{OH}	−13.4	—	mA	—

Table 27. MII Transmit AC Timing Specifications (continued)At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TX_CLK data clock rise (20%–80%)	t_{MTXR}	1.0	—	4.0	ns
TX_CLK data clock fall (80%–20%)	t_{MTXF}	1.0	—	4.0	ns

Note:

1. The symbols for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). In general, the clock reference symbol is based on two to three letters representing the clock of a particular function. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 11 shows the MII transmit AC timing diagram.

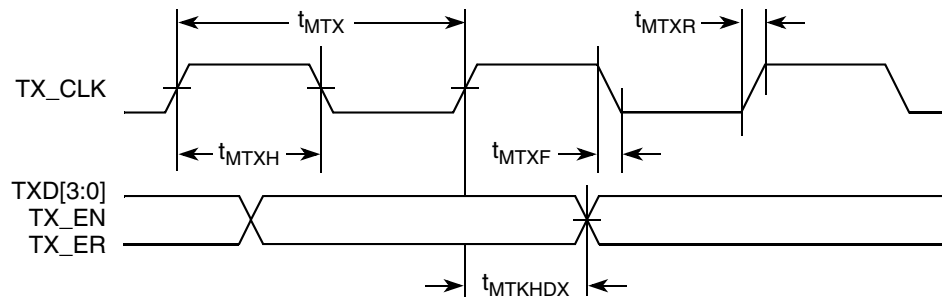
**Figure 11. MII Transmit AC Timing Diagram****8.2.2.2 MII Receive AC Timing Specifications**

Table 28 provides the MII receive AC timing specifications.

Table 28. MII Receive AC Timing SpecificationsAt recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns

Table 30. TBI Receive AC Timing Specifications (continued)At recommended operating conditions with LV_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RXD[7:0], RX_DV, RX_ER (RCG[9:0]) setup time to rising PMA_RX_CLK	t_{TRDVKH}^2	2.5	—	—	ns
RXD[7:0], RX_DV, RX_ER (RCG[9:0]) hold time to rising PMA_RX_CLK	t_{TRDXKH}^2	1.5	—	—	ns
RX_CLK clock rise time (20%–80%)	t_{TRXR}	0.7	—	2.4	ns
RX_CLK clock fall time (80%–20%)	t_{TRXF}	0.7	—	2.4	ns

Notes:

- The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. In general, the clock reference symbol is based on three letters representing the clock of a particular function. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript SK followed by the clock that is being skewed (TRX).
- Setup and hold time of even numbered RCG are measured from the rising edge of PMA_RX_CLK1. Setup and hold times of odd-numbered RCG are measured from the rising edge of PMA_RX_CLK0.

Figure 15 shows the TBI receive AC timing diagram.

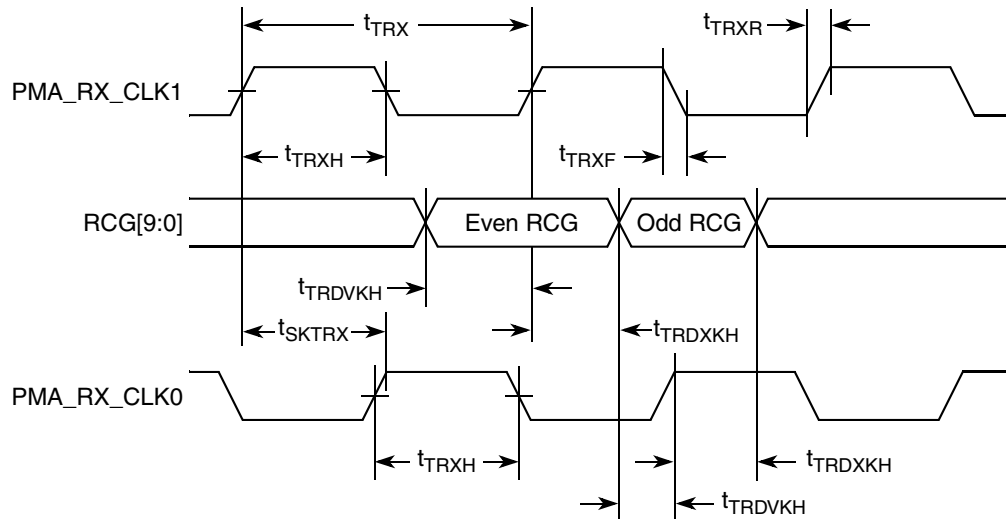
**Figure 15. TBI Receive AC Timing Diagram**

Table 32. MII Management DC Electrical Characteristics Powered at 2.5 V (continued)

Parameter	Symbol	Conditions	Min	Max	Unit
Input high current	I_{IH}	$V_{IN}^1 = LV_{DD}$	—	10	μA
Input low current	I_{IL}	$V_{IN} = LV_{DD}$	–15	—	μA

Note:

1. The symbol V_{IN} , in this case, represents the LV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

Table 33. MII Management DC Electrical Characteristics Powered at 3.3 V

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage (3.3 V)	LV_{DD}	—		2.97	3.63	V
Output high voltage	V_{OH}	$I_{OH} = -1.0 \text{ mA}$	$LV_{DD} = \text{Min}$	2.10	$LV_{DD} + 0.3$	V
Output low voltage	V_{OL}	$I_{OL} = 1.0 \text{ mA}$	$LV_{DD} = \text{Min}$	GND	0.50	V
Input high voltage	V_{IH}	—		2.00	—	V
Input low voltage	V_{IL}	—		—	0.80	V
Input high current	I_{IH}	$LV_{DD} = \text{Max}$	$V_{IN}^1 = 2.1 \text{ V}$	—	40	μA
Input low current	I_{IL}	$LV_{DD} = \text{Max}$	$V_{IN} = 0.5 \text{ V}$	–600	—	μA

Note:

1. The symbol V_{IN} , in this case, represents the LV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

8.3.2 MII Management AC Electrical Specifications

[Table 34](#) provides the MII management AC timing specifications.

Table 34. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD} is 3.3 V $\pm$ 10% or 2.5 V $\pm$ 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	—
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
MDC to MDIO delay	t_{MDKHDX}	10	—	70	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	—
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	—

Figure 30 provides the boundary-scan timing diagram.

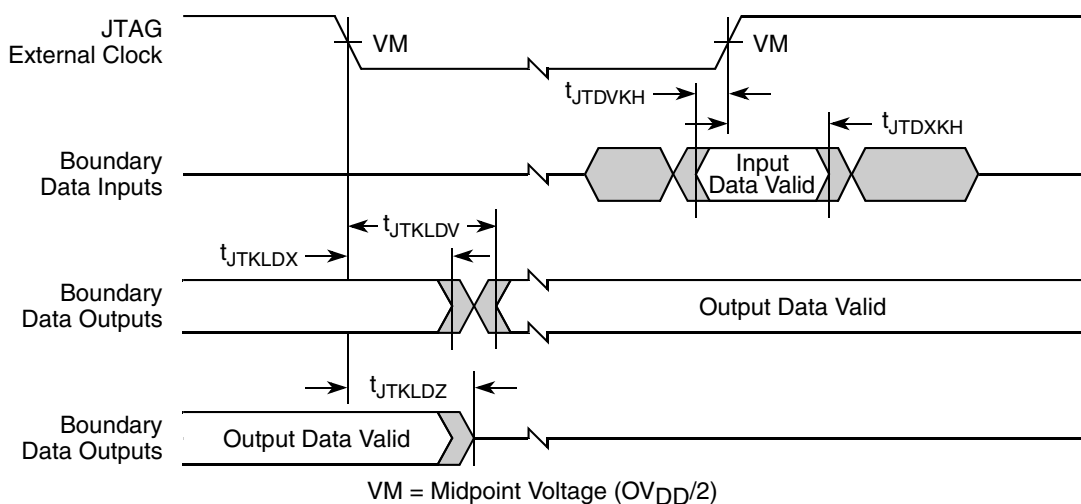


Figure 30. Boundary-Scan Timing Diagram

Figure 31 provides the test access port timing diagram.

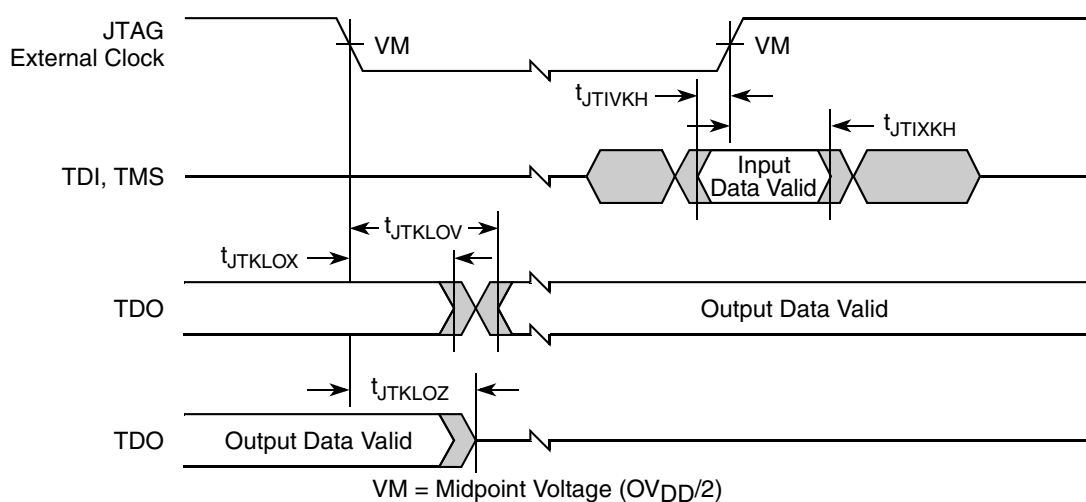


Figure 31. Test Access Port Timing Diagram

Table 43. I²C AC Electrical Specifications (continued)

Parameter	Symbol ¹	Min	Max	Unit
Fall time of both SDA and SCL signals ⁵	t_{I2CF}	—	300	ns
Setup time for STOP condition	t_{I2PVKH}	0.6	—	μ s
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μ s
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) goes invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaches the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. The device provides a hold time of at least 300 ns for the SDA signal (referred to the $V_{IH(min)}$ of the SCL signal) to bridge the undefined region of the falling edge of SCL.
3. The maximum t_{I2DVKH} must be met only if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. C_B = capacitance of one bus line in pF.
- 5.)The device does not follow the "I²C-BUS Specifications" version 2.1 regarding the t_{I2CF} AC parameter.

Figure 32 provides the AC test load for the I²C.

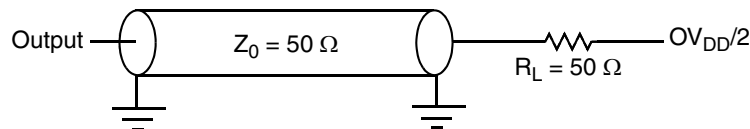
Figure 32. I²C AC Test Load

Figure 33 shows the AC timing diagram for the I²C bus.

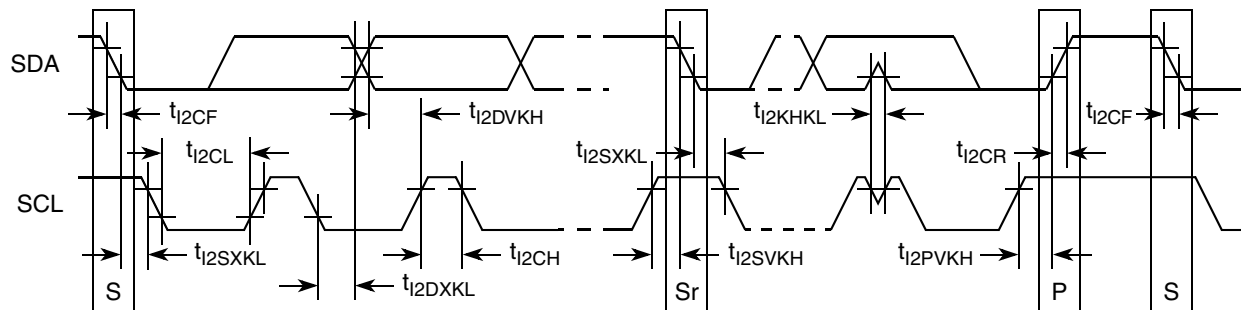
Figure 33. I²C Bus AC Timing Diagram

Table 47. Timer DC Electrical Characteristics (continued)

Parameter	Symbol	Condition	Min	Max	Unit
Output low voltage	V_{OL}	$I_{OL} = 8.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V

14.2 Timer AC Timing Specifications

Table 48 provides the timer input and output AC timing specifications.

Table 48. Timers Input AC Timing Specifications¹

Parameter	Symbol ²	Min	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:

1. Input specifications are measured from the 50 percent level of the signal to the 50 percent level of the rising edge of CLKIN. Timings are measured at the pin.
2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by external synchronous logic. Timer inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

15 GPIO

This section describes the DC and AC electrical specifications for the GPIO.

15.1 GPIO DC Electrical Characteristics

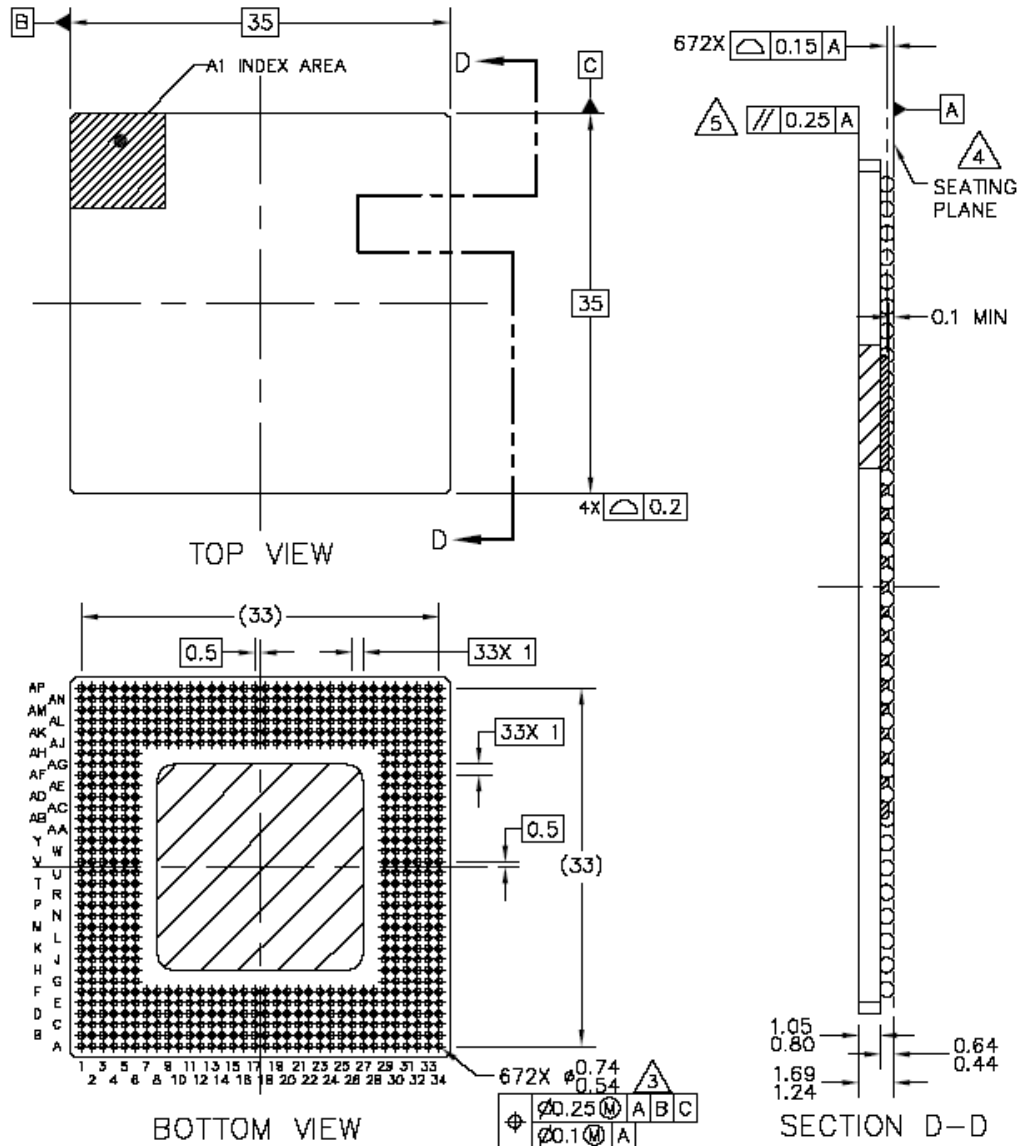
Table 49 provides the DC electrical characteristics for the MPC8349EA GPIO.

Table 49. GPIO DC Electrical Characteristics

Parameter	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	−0.3	0.8	V
Input current	I_{IN}	—	—	±5	μA
Output high voltage	V_{OH}	$I_{OH} = -8.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 8.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V

18.2 Mechanical Dimensions for the MPC8349EA TBGA

Figure 40 shows the mechanical dimensions and bottom surface nomenclature for the MPC8349EA, 672-TBGA package.



Notes:

1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement must exclude any effect of mark on top surface of package.

Figure 40. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC8349EA TBGA

Table 55. MPC8349EA (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TSEC2_TX_ER/GPIO1[24]	F14	I/O	OV _{DD}	—
TSEC2_TX_EN/GPIO1[12]	C5	I/O	LV _{DD2}	—
TSEC2_TX_CLK/GPIO1[30]	E14	I/O	OV _{DD}	—
UART				
UART_SOUT[1:2]/MSRCID[0:1]/LSRCID[0:1]	AK27, AN29	O	OV _{DD}	—
UART_SIN[1:2]/MSRCID[2:3]/LSRCID[2:3]	AL28, AM29	I/O	OV _{DD}	—
UART_CTS[1]/MSRCID4/LSRCID4	AP30	I/O	OV _{DD}	—
UART_CTS[2]/MDVAL/ LDVAL	AN30	I/O	OV _{DD}	—
UART_RTS[1:2]	AP31, AM30	O	OV _{DD}	—
I²C interface				
IIC1_SDA	AK29	I/O	OV _{DD}	2
IIC1_SCL	AP32	I/O	OV _{DD}	2
IIC2_SDA	AN31	I/O	OV _{DD}	2
IIC2_SCL	AM31	I/O	OV _{DD}	2
SPI				
SPIMOSI/LCS[6]	AN32	I/O	OV _{DD}	—
SPIMISO/LCS[7]	AP33	I/O	OV _{DD}	—
SPICLK	AK30	I/O	OV _{DD}	—
SPISEL	AL31	I	OV _{DD}	—
Clocks				
PCI_CLK_OUT[0:2]	AN9, AP9, AM10,	O	OV _{DD}	—
PCI_CLK_OUT[3]/LCS[6]	AN10	O	OV _{DD}	—
PCI_CLK_OUT[4]/LCS[7]	AJ11	O	OV _{DD}	—
PCI_CLK_OUT[5:7]	AP10, AL11, AM11	O	OV _{DD}	—
PCI_SYNC_IN/PCI_CLOCK	AK12	I	OV _{DD}	—
PCI_SYNC_OUT	AP11	O	OV _{DD}	3
RTC/PIT_CLOCK	AM32	I	OV _{DD}	—
CLKIN	AM9	I	OV _{DD}	—
JTAG				
TCK	E20	I	OV _{DD}	—
TDI	F20	I	OV _{DD}	4

Table 55. MPC8349EA (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
GND	A1, A34, C1, C7, C10, C11, C15, C23, C25, C28, D1, D8, D20, D30, E7, E13, E15, E17, E18, E21, E23, E25, E32, F6, F19, F27, F30, F34, G31, H5, J4, J34, K30, L5, M2, M5, M30, M33, N3, N5, P30, R5, R32, T5, T30, U6, U29, U33, V2, V5, V30, W6, W30, Y30, AA2, AA30, AB2, AB6, AB30, AC3, AC6, AD31, AE5, AF2, AF5, AF31, AG30, AG31, AH4, AJ3, AJ19, AJ22, AK7, AK13, AK14, AK16, AK18, AK20, AK25, AK28, AL3, AL5, AL10, AL12, AL22, AL27, AM1, AM6, AM7, AN12, AN17, AN34, AP1, AP8, AP34	—	—	—
GV _{DD}	A2, E2, G5, G6, J5, K4, K5, L4, N4, P5, R6, T6, U5, V1, W5, Y5, AA4, AB3, AC4, AD5, AF3, AG5, AH2, AH5, AH6, AJ6, AK6, AK8, AK9, AL6	Power for DDR DRAM I/O voltage (2.5 V)	GV _{DD}	—
LV _{DD1}	C9, D11	Power for three speed Ethernet #1 and for Ethernet management interface I/O (2.5 V, 3.3 V)	LV _{DD1}	—
LV _{DD2}	C6, D9	Power for three speed Ethernet #2 I/O (2.5 V, 3.3 V)	LV _{DD2}	—
V _{DD}	E19, E29, F7, F9, F11, F13, F15, F17, F18, F21, F23, F25, F29, H29, J6, K29, M29, N6, P29, T29, U30, V6, V29, W29, AB29, AC5, AD29, AF6, AF29, AH29, AJ8, AJ12, AJ14, AJ16, AJ18, AJ20, AJ21, AJ23, AJ25, AJ26, AJ27, AJ28, AJ29, AK10	Power for core (1.2 V nominal, 1.3 V for 667 MHz)	V _{DD}	—
OV _{DD}	B22, B28, C16, C17, C24, C26, D13, D15, D19, D29, E31, F28, G33, H30, L29, L32, N32, P31, R31, U32, W31, Y29, AA29, AC30, AE31, AF30, AG29, AJ17, AJ30, AK11, AL15, AL19, AL21, AL29, AL30, AM20, AM23, AM24, AM26, AM28, AN11, AN13	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	—
MVREF1	M3	I	DDR reference voltage	—

Table 58. System PLL Multiplication Factors (continued)

RCWL[SPMF]	System PLL Multiplication Factor
0111	× 7
1000	× 8
1001	× 9
1010	× 10
1011	× 11
1100	× 12
1101	× 13
1110	× 14
1111	× 15

As described in [Section 19, “Clocking,”](#) the LBIUCM, DDRCM, and SPMF parameters in the reset configuration word low and the CFG_CLKIN_DIV configuration input signal select the ratio between the primary clock input (CLKIN or PCI_CLK) and the internal coherent system bus clock (*csb_clk*). [Table 59](#) and [Table 60](#) show the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

Table 59. CSB Frequency Options for Host Mode

CFG_CLKIN_DIV at Reset ¹	SPMF	<i>csb_clk</i> : Input Clock Ratio ²	Input Clock Frequency (MHz) ²			
			16.67	25	33.33	66.67
			<i>csb_clk</i> Frequency (MHz)			
Low	0010	2 : 1				133
Low	0011	3 : 1				100
Low	0100	4 : 1				133
Low	0101	5 : 1				166
				100	133	266
				125	166	333

Table 59. CSB Frequency Options for Host Mode (continued)

CFG_CLKIN_DIV at Reset ¹	SPMF	csb_clk : Input Clock Ratio ²	Input Clock Frequency (MHz) ²			
			16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
Low	0110	6 : 1	100	150	200	
Low	0111	7 : 1	116	175	233	
Low	1000	8 : 1	133	200	266	
Low	1001	9 : 1	150	225	300	
Low	1010	10 : 1	166	250	333	
Low	1011	11 : 1	183	275		
Low	1100	12 : 1	200	300		
Low	1101	13 : 1	216	325		
Low	1110	14 : 1	233			
Low	1111	15 : 1	250			
Low	0000	16 : 1	266			
High	0010	2 : 1				133
High	0011	3 : 1			100	200
High	0100	4 : 1			133	266
High	0101	5 : 1			166	333
High	0110	6 : 1			200	
High	0111	7 : 1			233	
High	1000	8 : 1				

¹ CFG_CLKIN_DIV selects the ratio between CLKIN and PCI_SYNC_OUT.

² CLKIN is the input clock in host mode; PCI_CLK is the input clock in agent mode.

Table 60. CSB Frequency Options for Agent Mode

CFG_CLKIN_DIV at Reset ¹	SPMF	csb_clk : Input Clock Ratio ²	Input Clock Frequency (MHz) ²			
			16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
Low	0010	2 : 1				133
Low	0011	3 : 1				100
Low	0100	4 : 1				100
Low	0101	5 : 1				125

Table 61. e300 Core PLL Configuration

RCWL[COREPLL]			<i>core_clk</i> : <i>csb_clk</i> Ratio	VCO Divider ¹
0–1	2–5	6		
nn	0000	n	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)
00	0001	0	1:1	2
01	0001	0	1:1	4
10	0001	0	1:1	8
11	0001	0	1:1	8
00	0001	1	1.5:1	2
01	0001	1	1.5:1	4
10	0001	1	1.5:1	8
11	0001	1	1.5:1	8
00	0010	0	2:1	2
01	0010	0	2:1	4
10	0010	0	2:1	8
11	0010	0	2:1	8
00	0010	1	2.5:1	2
01	0010	1	2.5:1	4
10	0010	1	2.5:1	8
11	0010	1	2.5:1	8
00	0011	0	3:1	2
01	0011	0	3:1	4
10	0011	0	3:1	8
11	0011	0	3:1	8

¹ Core VCO frequency = core frequency × VCO divider. The VCO divider must be set properly so that the core VCO frequency is in the range of 800–1800 MHz.

- The e300 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in [Section 19.2, “Core PLL Configuration.”](#)

21.2 PLL Power Supply Filtering

Each PLL gets power through independent power supply pins (AV_{DD1} , AV_{DD2} , respectively). The AV_{DD} level should always equal to V_{DD} , and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme.

There are a number of ways to provide power reliably to the PLLs, but the recommended solution is to provide four independent filter circuits as illustrated in [Figure 42](#), one to each of the four AV_{DD} pins. Independent filters to each PLL reduce the opportunity to cause noise injection from one PLL to the other.

The circuit filters noise in the PLL resonant frequency range from 500 kHz to 10 MHz. It should be built with surface mount capacitors with minimum effective series inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

To minimize noise coupled from nearby circuits, each circuit should be placed as closely as possible to the specific AV_{DD} pin being supplied. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of package, without the inductance of vias.

[Figure 42](#) shows the PLL power supply filter circuit.

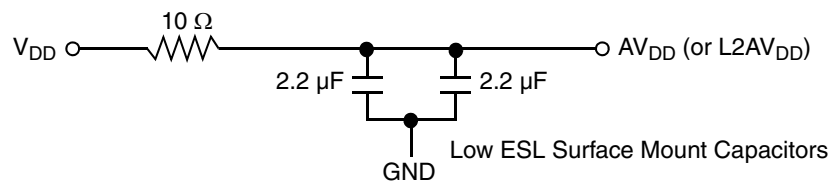


Figure 42. PLL Power Supply Filter Circuit

21.3 Decoupling Recommendations

Due to large address and data buses and high operating frequencies, the MPC8349EA can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the MPC8349EA system, and the device itself requires a clean, tightly regulated source of power. Therefore, the system designer should place at least one decoupling capacitor at each V_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} pin of the device. These capacitors should receive their power from separate V_{DD} , OV_{DD} , GV_{DD} , LV_{DD} , and GND power planes in the PCB, with short traces to minimize inductance. Capacitors can be placed directly under the device using a standard escape pattern. Others can surround the part.

These capacitors should have a value of 0.01 or 0.1 μF . Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0603 sizes.

In addition, distribute several bulk storage capacitors around the PCB, feeding the V_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should

$V_2 = (1 \div (1/R_1 + 1/R_2)) \times I_{\text{source}}$. Solving for the output impedance gives $R_{\text{source}} = R_{\text{term}} \times (V_1 \div V_2 - 1)$. The drive current is then $I_{\text{source}} = V_1 \div R_{\text{source}}$.

Table 65 summarizes the signal impedance targets. The driver impedance are targeted at minimum V_{DD} , nominal OV_{DD} , 105°C.

Table 65. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	PCI Signals (Not Including PCI Output Clocks)	PCI Output Clocks (Including PCI_SYNC_OUT)	DDR DRAM	Symbol	Unit
R_N	42 Target	25 Target	42 Target	20 Target	Z_0	W
R_P	42 Target	25 Target	42 Target	20 Target	Z_0	W
Differential	NA	NA	NA	NA	Z_{DIFF}	W

Note: Nominal supply voltages. See Table 1, $T_j = 105^\circ\text{C}$.

21.6 Configuration Pin Multiplexing

The MPC8349EA power-on configuration options can be set through external pull-up or pull-down resistors of 4.7 k Ω on certain output pins (see the customer-visible configuration pins). These pins are used as output only pins in normal operation.

However, while $\overline{\text{HRESET}}$ is asserted, these pins are treated as inputs, and the value on these pins is latched when $\overline{\text{PORESET}}$ deasserts. Then the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for the output pins.

21.7 Pull-Up Resistor Requirements

The MPC8349EA requires high resistance pull-up resistors (10 k Ω is recommended) on open-drain pins, including I²C pins, and IPIC interrupt pins.

For more information on required pull-up resistors and the connections required for the JTAG interface, refer to application note AN2931, “PowerQUICC Design Checklist.”

22 Ordering Information

This section presents ordering information for the device discussed in this document, and it shows an example of how the parts are marked.

NOTE

The information in this document is accurate for revision 3.x silicon and later (in other words, for orderable part numbers ending in A or B). For information on revision 1.1 silicon and earlier versions, see the *MPC8349E PowerQUICC II Pro Integrated Host Processor Hardware Specifications* (Document Order No. MPC8349EEC).

Table 68. Document Revision History (continued)

Rev. Number	Date	Substantive Change(s)
3	11/2006	- Updated note in introduction. - In the features list in Section 1, "Overview," updated DDR data rate to show 400 MHz for DDR2 for TBGA parts for silicon 3.x and 400 MHz for DDR2 for TBGA parts for silicon 3.x. - In Section 23, "Ordering Information," replicated note from document introduction.
2	8/2006	- Changed all references to revision 2.0 silicon to revision 3.0 silicon. - Changed VIH minimum value in Table 40, "JTAG Interface DC Electrical Characteristics," to $OV_{DD} - 0.3$. - In Table 44, "PCI DC Electrical Characteristics," changed high-level input voltage values to min = 2 and max = $OV_{DD} + 0.3$; changed low-level input voltage values to min = (-0.3) and max = 0.8. - Updated DDR2 I/O power values in Table 5, "MPC8347EA Typical I/O Power Dissipation." - In Table 66, "Suggested PLL Configurations," deleted reference-number rows 902 and 703.
1	4/2006	- Removed Table 20, "Timing Parameters for DDR2-400." - Changed ADDR/CMD to ADDR/CMD/MODT in Table 9, "DDR and DDR2 SDRAM Output AC Timing Specifications," rows 2 and 3, and in Figure 2, "DDR SDRAM Output Timing Diagram." - Changed Min and Max values for V_{IH} and V_{IL} in Table 40Table 44, "PCI DC Electrical Characteristics." - In Table 55, "MPC8349EA (TBGA) Pinout Listing," and Table 52, "MPC8347EA (PBGA) Pinout Listing," modified rows for MDICO and MDIC1 signals and added note 'It is recommended that MDICO be tied to GRD using an 18 Ω resistor and MCIC1 be tied to DDR power using an 18 Ω resistor.' - Table 55, "MPC8349EA (TBGA) Pinout Listing," in row AVDD3 changed power supply from "AVDD3" to '—.'
0	3/2006	Initial public release